



新普科技股份有限公司
 新世電子(常熟)有限公司
 新普科技(重慶)有限公司
 華普電子(常熟)有限公司

Control NO: LE-CU-15-01-041

UN38.3 Test Report

Recommendations on the TRANSPORT OF DANGEROUS GOODS

(Manual of Tests and Criteria, Fifth revised edition, Amend 1)

Customer: Lenovo

Model: L14M2P23

Rating: 7.4V, 30Wh, 4050mAh

Test duration: 2014/12/29~2015/01/23

Approved By	Checked By	Prepared By
Winel Zhao	Winel Zhao	Happy-Gu.

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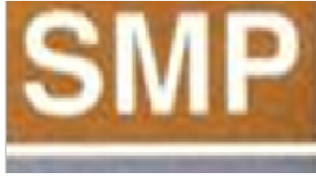


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Page 1 of 7

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1. Purpose of the Test:

To test each cell/battery is of the type proved to meet the requirements in the Recommendations on the TRANSPORT OF DANGEROUS GOODS, Manual of Tests and Criteria, Fifth revised edition, Amend 1.

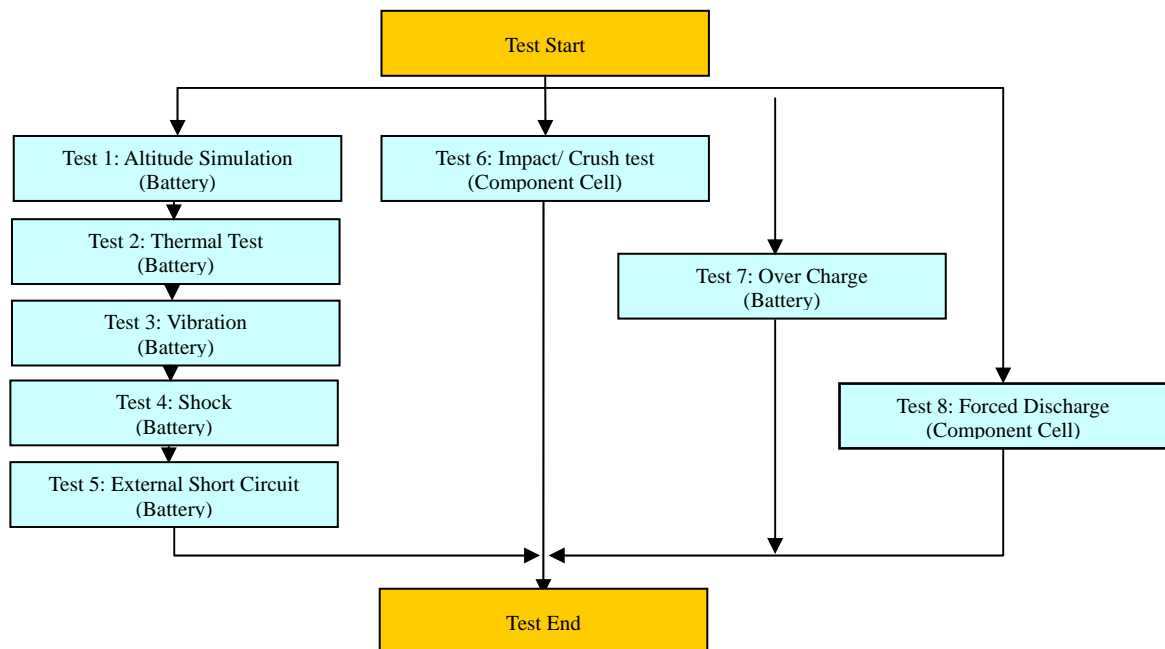
2. Test Quantity:

- 2.1 Four batteries, at first cycle, in fully charged states. (T.1~T.5 test only)
- 2.2 Four batteries, after fifty cycles ending in fully charged states. (T.1~T.5 test only)
- 2.3 Five component cells, at first cycle at 50% of the design rated capacity. (T.6 test only)
- 2.4 Four batteries, at first cycle, in fully charged states. (T.7 test only)
- 2.5 Four batteries, after fifty cycles ending in fully charged states. (T.7 test only)
- 2.6 Ten component cells, at first cycle in fully discharge states. (T.8 test only)
- 2.7 Ten component cells, after fifty cycles ending in fully discharged states. (T.8 test only)

3. Test procedure:

3.1 All detail related test procedure shall be follow Standard Operation Procedure of SMP subjected CW01-5916 Rev.4 issue documentation.

3.2 Test flow shall be follow below statement.





4. Test Result:

4.1 T.1 ~T.4 Test result: **Passed**

- 4.1.1 All batteries could meet the requirement, mass loss was less than 0.1% and residual OCV not less than 90% after the test.
- 4.1.2 No leakage, no venting, no disassembly, no rupture and no fire.

4.2 T.5 Test result: **Passed**

- 4.2.1 All batteries could meet the requirement, external temperature did not exceed 170 .
- 4.2.2 All batteries were no disassembly, no rupture and no fire during the test and within six hours after the test.

4.3 T.6 Test result: **Passed**

- 4.3.1 All component cells could meet the requirement, external temperature did not exceed 170 .
- 4.3.2 All component cells were no disassembly and no fire during the test and within six hours after the test.

4.4 T.7 Test result: **Passed**

- 4.4.1 All batteries could meet no disassembly and no fire during the test and within seven days after the test.

4.5 T.8 Test result: **Passed**

- 4.5.1 All component cells could meet the requirement, no disassembly and no fire during the test and within seven days after the test.

Conclusion: The samples had passed the test items of UN38.3.



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Control NO: LE-CU-15-01-041

5. Test Equipment:

SMP 新世電子(常熟)有限公司 Address : No.2 Dong Nan Avenue, Changshu, Jingsu Province, China TEL: 0512-52302255 FAX: 0512-52302277									
Revised date: 2014/12/30 Date 2014/12/29~2015/01/23 Model name: L14MCP23									
Test Instruments Reference List									
Used	Instrument [D](New)	Instrument [D](Old)	Instrument Name	Type	Range Used	Manufacturer	CalibrationDate_Last	Calibration Date_Next	Remarks
Pretest									
V	EE01-CA-100002	C602M00/S0096	715 learning機	新普科技	18V/8A	新普科技	2014/12/30	2015/1/22/9	
V	EE03-CA-100018	C602M00/S0107	720 learning機	新普科技	Chang:18V/17A Discharge:16V/18A	新普科技	2014/3/10	2015/3/8	
V	EE01-CA-100003	C602M00/S0099	715 learning機	新普科技	18V/8A	新普科技	2014/03/10	2015/03/09	
V	EE01-CA-100005	C602M00/S0098	715 learning機	新普科技	18V/8A	新普科技	2014/04/09	2015/04/08	
V	EE03-CA-100020	C602M00/S0163	720 learning機	新普科技	Chang:18V/17A Discharge:16V/18A	新普科技	2014/10/21	2015/1/02/0	
Low Pressure Test									
V	EC15-CA-E00003	C602M00/0462	Altitude	SVT-110	Kpa: 0~99Kpa	HSIN JIANG	2014/09/08	2015/09/07	
V	EA02-CA-100002	C602M00/0293	mΩ Hitester	3561	R:-10~310mΩ V:20~20V	HIOKI	2014/9/17	2015/9/16	
V	EF03-CA-100001	C602M00/C0604	Electronic Balance	X51220M-SCS	1220g±0.001g	CHENGZHUN	2014/10/21	2015/1/02/0	
V	ED01-CA-100007	C602M00/T0412	Thermo Meter	TA218	T: -10℃~70℃ RH: 25%~98%	KTJ	2014/8/27	2015/8/26	
Thermal Test									
V	EC29-CA-E00002	C602M00/0671	Thermal Shock	TSK-A4C-150	T:-65℃ to 150℃	KSON	2014/06/09	2015/06/08	
V	EA02-CA-100002	C602M00/0293	mΩ Hitester	3561	R:-10~310mΩ V:20~20V	HIOKI	2014/9/17	2015/9/16	
V	EF03-CA-100001	C602M00/C0604	Electronic Balance	X51220M-SCS	1220g±0.001g	CHENGZHUN	2014/10/21	2015/1/02/0	
V	ED01-CA-100007	C602M00/T0412	Thermo Meter	TA218	T: -10℃~70℃ RH: 25%~98%	KTJ	2014/8/27	2015/8/26	
Vibration Test									
V	EC08-CA-E00001	C602M00/0197	Vibration	EM-200F2K-25N	F:3~2000Hz G:0.2~55G	King Design	2014/3/12	2015/3/11	
V	EC08-CA-E00002	C602M00/0052	Vibration	EM-200F2K-25N	F:3~2000Hz G:0.2~55G	King Design	2014/9/24	2015/9/23	
V	EA02-CA-100002	C602M00/0293	mΩ Hitester	3561	R:-10~310mΩ V:20~20V	HIOKI	2014/9/17	2015/9/16	
V	EF03-CA-100001	C602M00/C0604	Electronic Balance	X51220M-SCS	1220g±0.001g	CHENGZHUN	2014/10/21	2015/1/02/0	
Shock Test									
V	EC17-CA-E00001	C602M00/0570	Shock	HS 1545	G:10~2000G	Lansmont	2014/09/08	2015/09/07	
V	EA02-CA-100002	C602M00/0293	mΩ Hitester	3561	R:-10~310mΩ V:20~20V	HIOKI	2014/9/17	2015/9/16	
V	EF03-CA-100001	C602M00/C0604	Electronic Balance	X51220M-SCS	1220g±0.001g	CHENGZHUN	2014/10/21	2015/1/02/0	
External Short Circuit Test									
V	EA02-CA-100002	C602M00/0293	mΩ Hitester	3561	R:-10~310mΩ V:20~20V	HIOKI	2014/9/17	2015/9/16	
V	EA09-CA-100004	C602M00/0207	Data logger	34970A	V: 0~300V, T: -150℃~1200℃	Agilent	2014/09/17	2015/09/16	
V	EC26-CA-100023	C602M00/0518	chamber	WIT TH-2P-E	-40℃ to 150℃	WIT	2014/08/11	2015/08/10	
V	ED01-CA-100007	C602M00/T0412	Thermo Meter	TA218	T: -10℃~70℃ RH: 25%~98%	KTJ	2014/8/27	2015/8/26	
Impact Test/Crush Test									
V	EC17-CA-100001	C602M00/1204	Impact test	100-372	H 60~80cm	JYI SHENG	2014/9/17	2015/9/16	
V	EC23-CA-E00001	C602M00/0743	Crush Test	BE-6047	1.0KN~15.0KN	BELL	2014/09/08	2015/09/07	
V	EA09-CA-100005	C602M00/0588	Data logger	34970A	V: 0~300V, T: -150℃~1200℃	Agilent	2014/09/17	2015/09/16	
V	ED01-CA-100010	C602M00/T0581	Thermo Meter	TA218	T: -10℃~70℃ RH: 25%~98%	KTJ	2014/6/22	2015/6/21	
Overcharge Test									
V	EA06-CA-E00003	C602M00/P0779	Power Supply	DS6024	0~60V 0~2.4A	MOTECH	2014/03/12	2015/03/11	
V	EA06-CA-E00002	C602M00/P0777	Power Supply	DS6024	0~60V 0~2.4A	MOTECH	2014/03/12	2015/03/11	
V	EA06-CA-E00001	C602M00/P0775	Power Supply	DS6024	0~60V 0~2.4A	MOTECH	2014/03/12	2015/03/11	
V	EA06-CA-E00004	C602M00/P0781	Power Supply	DS6024	0~60V 0~2.4A	MOTECH	2014/03/12	2015/03/11	
V	ED01-CA-100007	C602M00/T0412	Thermo Meter	TA218	T: -10℃~70℃ RH: 25%~98%	KTJ	2014/8/27	2015/8/26	
Forced Discharge Test									
V	EA06-CA-100004	/	Power Supply	E3633A	0~8V 20A,0~20V,10A	AGILENT	2014/9/17	2015/9/16	
V	EA06-CA-100016	/	Power Supply	E3633A	0~8V 20A,0~20V,10A	AGILENT	2014/5/10	2015/5/8	
V	EA06-CA-100015	C602M00/P0481	Power Supply	E3633A	0~8V 20A,0~20V,10A	AGILENT	2014/5/10	2015/5/8	
V	EA05-CA-100006	/	Electronic LOAD	3311D	60V,60A, 300W	PRODIGIT	2014/05/12	2015/05/11	
V	EA05-CA-100009	/	Electronic LOAD	3311F	60V,60A, 300W	PRODIGIT	2014/05/12	2015/05/11	
V	EA05-CA-100008	C602M00/L0402	Electronic LOAD	3311F	60V,60A, 300W	PRODIGIT	2014/08/13	2015/08/12	

Note 1: DC Voltage: 0.1~1000V; AC Voltage: 0.5~700V @ 60Hz, 1kHz; Resistance: 10Ω~10MΩ; DC current:0.1mA~3A; AC current: 0.01mA~3A at 60Hz, 0.01mA~1A, at 1kHz

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Control NO: LE-CU-15-01-041

6. T.1~T8 detail reports:

Control No.:LE-CU-15-01-041

UN 38.3 Test Datasheet

Customer:Lenovo

Model Name:L14M2P23

Test Duration:2014/12/29-2015/01/23

Reviewer:Wind_Zhao

Test Sample Identification:

Battery					Component Cell			
Used	Sample No.	Sample State	Used	Sample No.	Sample State	Used	Sample No.	Sample State
V	1~4	1 Cycle, Fully charged	V	5~8	50 Cycle, Fully charged	V	1C~5C	1 Cycle, 50% charged
V	9~12	1 Cycle, Fully charged	V	13~16	50 Cycle, Fully charged	V	6C~15C	1 Cycle, 0% charged
		25Cycle, Fully charged			25 Cycle, Fully charged	V	16C~25C	50 Cycle, 0% charged

T.1 Altitude Simulation Start time:2015/01/12 08:20 Ambient temp.: 22.7 °C Operator: Happy_Gu
 Finish time:2015/01/12 17:30

Sample No.: 01					Sample No.: 02					
	Before	After	Variation	Results		Before	After	Variation	Results	
Mass (g)	143.5	143.5	Mass loss %	0.01%	P	Mass (g)	143.1	143.0	Mass loss %	0.01%
OCV (V)	8.30	8.28	Residual OCV %	99.75%		OCV (V)	8.31	8.28	Residual OCV %	99.71%
Sample No.: 03					Sample No.: 04					
Mass (g)	143.6	143.6	Mass loss %	0.01%	P	Mass (g)	142.5	142.5	Mass loss %	0.01%
OCV (V)	8.31	8.29	Residual OCV %	99.71%		OCV (V)	8.29	8.27	Residual OCV %	99.71%
Sample No.: 05					Sample No.: 06					
Mass (g)	143.0	143.0	Mass loss %	0.01%	P	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.31	8.28	Residual OCV %	99.69%		OCV (V)	8.29	8.27	Residual OCV %	99.71%
Sample No.: 07					Sample No.: 08					
Mass (g)	142.6	142.6	Mass loss %	0.01%	P	Mass (g)	142.9	142.9	Mass loss %	0.01%
OCV (V)	8.30	8.28	Residual OCV %	99.74%		OCV (V)	8.30	8.28	Residual OCV %	99.70%

T.2 Thermal Test Start time:2015/01/12 17:40 Ambient temp.: 19.5 °C Operator: Happy_Gu
 Finish time:2015/01/19 08:20

Sample No.: 01					Sample No.: 02					
	Before	After	Variation	Results		Before	After	Variation	Results	
Mass (g)	143.5	143.5	Mass loss %	0.01%	P	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.28	8.16	Residual OCV %	98.53%		OCV (V)	8.28	8.16	Residual OCV %	98.56%
Sample No.: 03					Sample No.: 04					
Mass (g)	143.6	143.6	Mass loss %	0.01%	P	Mass (g)	142.5	142.5	Mass loss %	0.01%
OCV (V)	8.29	8.17	Residual OCV %	98.59%		OCV (V)	8.27	8.14	Residual OCV %	98.50%
Sample No.: 05					Sample No.: 06					
Mass (g)	143.0	142.9	Mass loss %	0.01%	P	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.28	8.16	Residual OCV %	98.54%		OCV (V)	8.27	8.15	Residual OCV %	98.57%
Sample No.: 07					Sample No.: 08					
Mass (g)	142.6	142.6	Mass loss %	0.01%	P	Mass (g)	142.9	142.9	Mass loss %	0.01%
OCV (V)	8.28	8.16	Residual OCV %	98.51%		OCV (V)	8.28	8.15	Residual OCV %	98.50%

T.3 Vibration Start time:2015/01/19 08:40 Ambient temp.: 20.7 °C Operator: Happy_Gu
 Finish time:2015/01/20 08:20

Sample No.: 01					Sample No.: 02					
	Before	After	Variation	Results		Before	After	Variation	Results	
Mass (g)	143.5	143.5	Mass loss %	0.01%	P	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.16	8.04	Residual OCV %	98.47%		OCV (V)	8.16	8.04	Residual OCV %	98.51%
Sample No.: 03					Sample No.: 04					
Mass (g)	143.6	143.6	Mass loss %	0.01%	P	Mass (g)	142.5	142.5	Mass loss %	0.01%
OCV (V)	8.17	8.05	Residual OCV %	98.53%		OCV (V)	8.14	8.02	Residual OCV %	98.48%
Sample No.: 05					Sample No.: 06					
Mass (g)	142.9	142.9	Mass loss %	0.01%	P	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.16	8.04	Residual OCV %	98.49%		OCV (V)	8.15	8.03	Residual OCV %	98.52%
Sample No.: 07					Sample No.: 08					
Mass (g)	142.6	142.6	Mass loss %	0.01%	P	Mass (g)	142.9	142.9	Mass loss %	0.01%
OCV (V)	8.16	8.04	Residual OCV %	98.53%		OCV (V)	8.15	8.03	Residual OCV %	98.48%

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Control NO: LE-CU-15-01-041

T.4 Shock									
Start time:2015/01/20 08:40					Ambient temp.: 21.4 ℃				
Finsh time:2015/01/21 09:50					Operator: Happy_Gu				
Sample No.: 01					Sample No.: 02				
Before	After	Variation		Results	Before	After	Variation		Results
Mass (g)	143.5	143.5	Mass loss %	0.01%	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.04	8.01	Residual OCV %	99.74%	OCV (V)	8.04	8.02	Residual OCV %	99.75%
Sample No.: 03					Sample No.: 04				
Before	After	Variation		Results	Before	After	Variation		Results
Mass (g)	143.6	143.5	Mass loss %	0.01%	Mass (g)	142.5	142.4	Mass loss %	0.01%
OCV (V)	8.05	8.03	Residual OCV %	99.70%	OCV (V)	8.02	8.00	Residual OCV %	99.71%
Sample No.: 05					Sample No.: 06				
Before	After	Variation		Results	Before	After	Variation		Results
Mass (g)	142.9	142.9	Mass loss %	0.01%	Mass (g)	143.0	143.0	Mass loss %	0.01%
OCV (V)	8.04	8.01	Residual OCV %	99.70%	OCV (V)	8.03	8.01	Residual OCV %	99.74%
Sample No.: 07					Sample No.: 08				
Before	After	Variation		Results	Before	After	Variation		Results
Mass (g)	142.6	142.6	Mass loss %	0.01%	Mass (g)	142.9	142.9	Mass loss %	0.01%
OCV (V)	8.04	8.02	Residual OCV %	99.71%	OCV (V)	8.03	8.01	Residual OCV %	99.73%

T.5 External Short Circuit																		
Start time:2015/01/21 10:10								Ambient temp.: 20.6 ℃										
Finsh time:2015/01/22 08:30								Operator: Happy_Gu										
	Sample No.: 01	Sample No.: 02	Sample No.: 03	Sample No.: 04	Sample No.: 05	Sample No.: 06	Sample No.: 07	Sample No.: 08		Sample No.: 01	Sample No.: 02	Sample No.: 03	Sample No.: 04	Sample No.: 05	Sample No.: 06	Sample No.: 07	Sample No.: 08	
Resistance (<100mΩ)	59.7	56.4	55.8	57.2	56.8	56.2	56.9	58.4										
OCV before test/after short circuit(V)	8.01	0.00	8.02	0.00	8.03	0.00	8.00	0.00	8.01	0.00	8.01	0.00	8.01	0.00	8.02	0.00	8.01	0.00
Max Temp. (< 170℃)	54.8	55.1	55.2	54.8	54.9	55.5	55.6	55.2										
Results	P	P	P	P	P	P	P	P	P	P	P	P	P	P	P	P	P	P

T.6 Impact / Crush (Component Cell)											
Start time:2015/01/06 08:30					Ambient temp.: 19.4 ℃						
Finsh time:2015/01/06 18:40					Operator: Happy_Gu						
<input type="checkbox"/> Impact- Cylindrical cells greater than 20mm in diameter <input checked="" type="checkbox"/> Crush- Prismatic, pouch, coin/button cells and cylindrical cells not more than 20mm in diameter											
	Sample No.: 01C	Sample No.: 02C	Sample No.: 03C	Sample No.: 04C	Sample No.: 05C		Sample No.: 01C	Sample No.: 02C	Sample No.: 03C	Sample No.: 04C	Sample No.: 05C
OCV before test(V)	3.71	3.70	3.72	3.71	3.71						
Max Temp. (< 170℃)	26.4	24.4	25.1	24.7	24.5						
Results	P	P	P	P	P						

T.7 Overcharge								
Start time:2015/01/14 10:20					Ambient temp.: 18.9 ℃			
Finsh time:2015/01/23 14:10					Operator: Happy_Gu			
	Sample No.: 09	Sample No.: 10	Sample No.: 11	Sample No.: 12	Sample No.: 13	Sample No.: 14	Sample No.: 15	Sample No.: 16
OCV before test(V)	8.31	8.30	8.31	8.30	8.29	8.30	8.29	8.30
Results	P	P	P	P	P	P	P	P

T.8 Forced Discharge (Component Cell)											
Start time:2015/01/13 08:30					Ambient temp.: 20.4 ℃						
Finsh time:2015/01/22 13:30					Operator: Happy_Gu						
	Sample No.: 06C	Sample No.: 07C	Sample No.: 08C	Sample No.: 09C	Sample No.: 10C		Sample No.: 11C	Sample No.: 12C	Sample No.: 13C	Sample No.: 14C	Sample No.: 15C
OCV before test(V)	3.18	3.19	3.18	3.18	3.18						
Results	P	P	P	P	P						
	Sample No.: 16C	Sample No.: 17C	Sample No.: 18C	Sample No.: 19C	Sample No.: 20C		Sample No.: 21C	Sample No.: 22C	Sample No.: 23C	Sample No.: 24C	Sample No.: 25C
OCV before test(V)	3.20	3.19	3.18	3.20	3.19						
Results	P	P	P	P	P						
	Sample No.: 21C	Sample No.: 22C	Sample No.: 23C	Sample No.: 24C	Sample No.: 25C						
OCV before test(V)	3.19	3.20	3.18	3.18	3.20						
Results	P	P	P	P	P						

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Control NO: LE-CU-15-01-041

7. Test sample:



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